SN54HCT540, SN74HCT540 OCTAL BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

SCLS008B - MARCH 1984 - REVISED MAY 1997

- Inputs Are TTL-Voltage Compatible
- High-Current 3-State Outputs Interface Directly With System Bus or Can Drive up to 15 LSTTL Loads
- Data Flow-Through Pinout (All Inputs on Opposite Side From Outputs)
- Package Options Include Plastic Small-Outline (DW) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

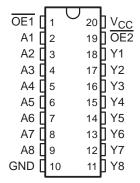
description

These octal buffers and line drivers are designed to have the performance of the 'HCT240 and a pinout with inputs and outputs on opposite sides of the package. This arrangement greatly facilitates printed circuit board layout.

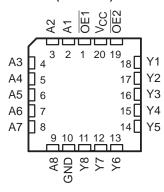
The 3-state control gate is a 2-input NOR. If either output-enable (OE1 or OE2) input is high, all eight outputs are in the high-impedance state. The 'HCT540 provide inverted data at the outputs.

The SN54HCT540 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HCT540 is characterized for operation from –40°C to 85°C.

SN54HCT540 ... J OR W PACKAGE SN74HCT540 ... DW OR N PACKAGE (TOP VIEW)



SN54HCT540 . . . FK PACKAGE (TOP VIEW)



FUNCTION TABLE (each buffer/driver)

	INPUTS	OUTPUT	
OE1	OE2	Α	Y
L	L	L	Н
L	L	Н	L
Н	X	Χ	Z
Χ	Н	Χ	Z



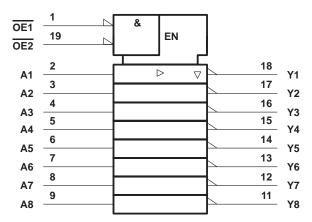
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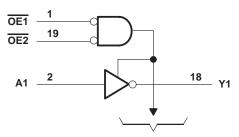
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logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Seven Other Channels

absolute maximum ratings over operating free-air temperature range‡

Supply voltage range, V _{CC}	0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±35 mA
Continuous current through V _{CC} or GND	±70 mA
Package thermal impedance, θ_{JA} (see Note 2): DW package	97°C/W
N package	67°C/W
Storage temperature range, T _{stg}	. −65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



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recommended operating conditions

				54HCT5	40	SN	UNIT		
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	2			2			V
V _{IL}	Low-level input voltage	V _{CC} = 4.5 V to 5.5 V	0		0.8	0		0.8	V
٧ _I	Input voltage		0		VCC	0		VCC	V
٧o	Output voltage		0		VCC	0		VCC	V
t _t	Input transition (rise and fall) time		0		500	0		500	ns
TA	Operating free-air temperature		– 55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		Vaa	T _A = 25°C			SN54HCT540		SN74HCT540		UNIT
PARAMETER			vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
Vou	VI = VIH or VIL	I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		V
Voн	AI = AIH OL AIL	$I_{OH} = -6 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		V
Va	V	I _{OL} = 20 μA	4.5 V		0.001	0.1		0.1		0.1	V
VOL	$V_I = V_{IH}$ or V_{IL}	I _{OL} = 6 mA	4.5 V		0.17	0.26		0.4		0.33	l v
lį	VI = VCC or 0		5.5 V		±0.1	±100		±1000		±1000	nA
loz	$V_O = V_{CC}$ or 0,	$V_I = V_{IH} \text{ or } V_{IL}$	5.5 V		±0.01	±0.5		±10		±5	μΑ
^I CC	$V_I = V_{CC}$ or 0,	I _O = 0	5.5 V			8		160		80	μΑ
ΔI _{CC} †	One input at 0.5 V one of the of the order inputs at 0 or		5.5 V		1.4	2.4		3		2.9	mA
Ci			4.5 V to 5.5 V		3	10		10		10	pF

[†] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	T,	Վ = 25° C	;	SN54H	CT540	SN74H	CT540	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
+ .	t _{pd} A		4.5 V		13	20		30		25		
ιрα		Y	5.5 V		12	18		27		23	ns	
	ŌĒ		4.5 V		20	30		45		38	ns	
t _{en}		1	1	5.5 V		18	27		41		34	115
4		DE Y	4.5 V		19	30		45		38	no	
^t dis	OE '		5.5 V		18	27		41		34	ns	
		V	V	4.5 V		8	12		18		15	nc
t _t		Ť	5.5 V		7	11		16		14	ns	

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switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

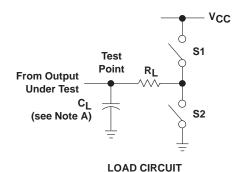
PARAMETER	FROM TO		Vaa	T,	λ = 25°C	;	SN54H	CT540	SN74H	CT540	UNIT					
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT					
	t _{pd} A	Y	4.5 V		20	30		45		38	no					
^t pd			1 5	'	'	ı ı		5.5	5.5 V	19	27		41		34	ns
•		v	4.5 V		26	40		60		50	no					
^t en	ŌĒ	Ť	T	, , , , , , , , , , , , , , , , , , ,	1	'	'	5.5 V		25	36		54		45	ns
		V	4.5 V		17	42		63		53	no					
it		Y	5.5 V		14	38		57		48	ns					

operating characteristics, $T_A = 25^{\circ}C$

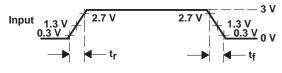
	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per buffer/driver	No load	35	pF

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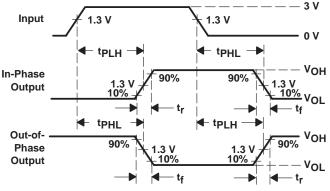
PARAMETER MEASUREMENT INFORMATION

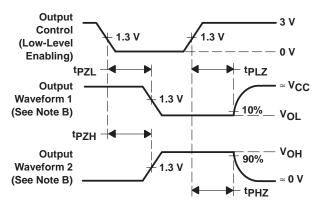


PARA	PARAMETER		CL	S1	S2	
	tPZH 50 pF		Open	Closed		
^t en	tPZL	1 K22	or 150 pF	Closed	Open	
t e.	tPHZ 1 kΩ		50 pF	Open	Closed	
^t dis	tPLZ	1 K22	30 pr	Closed	Open	
t _{pd} or t _t			50 pF or 150 pF	Open	Open	



VOLTAGE WAVEFORM INPUT RISE AND FALL TIMES





VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT RISE AND FALL TIMES

VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_Q = 50 \Omega$, $t_f = 6$ ns.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms

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